

Effect of internal radiation on the crystal-melt interface shape in Czochralski oxide growth

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Introduction.

Most oxide crystals (BGO, BSO, BTO, YAG, GGG) display transparency to infrared radiation that can greatly influence the crystal-melt interface shape during Czochralski growth since an additional mechanism arises for a heat removal from the vicinity of the crystallization front. Additional important factor affecting upon the shape of solid/liquid interface is related to the **Fresnel's reflection** (refraction) at **the transparent crystal surface** [1].

In practice:

1. The shape of real crystals can be appreciably differed from a regular cylinder or a cone that has to lead to scattering of radiation at the crystal surface and, consequently, to smoothing of the radiation heat flux distribution at the melt/solid interface.
2. Many oxide crystals demonstrate the pronounced tendency toward faceting of the solidification front that imply considerable supercooling at the faceted interface which should be taken into account in global simulation.

Note:

Up to now numerical calculation of facet formation was performed only for Bridgman process and internal radiation transport was treated using either the Rosseland diffusion approximation [2] or P_1 -approximation [3]

The objectives of the modeling:

1. To investigate the influence of deflections in the shape of a real crystal from conical and cylindrical geometry on the distributions of radiative heat flux over the crystallization front.
2. To investigate the effect of internal radiation and Fresnel reflection at the crystal surface on the process of facet formation in Cz oxides growth.

As a representative growth process, the $\text{Bi}_4\text{Ge}_3\text{O}_{12}$ low-thermal gradients Cz growth was considered (see Fig.A).

Characteristics of growth process

Melting temperature: $T_m = 1323 \text{ K}$
 Radiative and thermal properties of the crystal:
 • Thermal conductivity: $\kappa_s = 1.2 \text{ W/(m}\cdot\text{K)}$
 • Refractive index: $n = 2.15$
 • Absorption coefficient k is approximated by three-bands model:
 $\lambda < 4 \mu\text{m}$ $k = 3.0 \text{ m}^{-1}$
 $4 < \lambda < 6 \mu\text{m}$ $k = 95.5 \text{ m}^{-1}$
 $\lambda > 6 \mu\text{m}$ $k = \infty$

• Crystal cone angle $\alpha = 45^\circ$

• Radiative properties of other materials:

• Crucible emissivity (platinum): $\epsilon_c = 0.15$
 • Emissivity of a free melt surface: $\epsilon_l = 0.18$

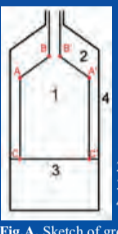


Fig.A. Sketch of growth set-up.

Description of the problem

Radiative problem for the crystals with perturbed surfaces and flat crystallization front was solved. The actual (known from the experiment) temperature distribution over the crucible wall was used as a boundary condition.

Results of the calculations are presented in Fig.1.1-1.5 and 2.1-2.5 in a view of temperature fields in the crystal and heat flux q removing from the crystallization front (see Fig. 1.6 and 2.5):

$$q = q_{cr} e_{cr} = \left(-\frac{\partial T}{\partial n} + q_{rad} \right) e_{cr}$$

where q_{rad} is the density of the net radiative flux at the solid-melt interface in the range of semi-transparency of the crystal.

Description of disturbances:

Radial disturbance of the crystal side surface (see Fig.1.1-1.5) were given in the following form:

$$R = R_0 + \epsilon_1 \sin \frac{2m_1 z}{L}$$

Perturbations on the conical part of the crystal side surface (see Fig.3.1-3.5) were given as follows:

$$Z = R_0 \cot \alpha + z - r \cot \alpha - \epsilon_2 \sin \frac{2m_2 r}{R_0}$$

where:

- R_0 – base radius of a crystal
- R – current radius of a crystal for wave perturbations.
- ϵ_1, ϵ_2 – perturbation amplitude
- L – crystal length
- m_1, m_2 – numbers of periods of perturbations on the surface
- α – cone angle

I.1 Effect of deflection of a cylinder's generatrix from a straight line.

From cases 1 to 4 specular reflection takes place both on the conical and cylindrical surfaces. For the case 5 reflection on the conical part of crystal surface is specular and on the cylindrical one is diffuse.

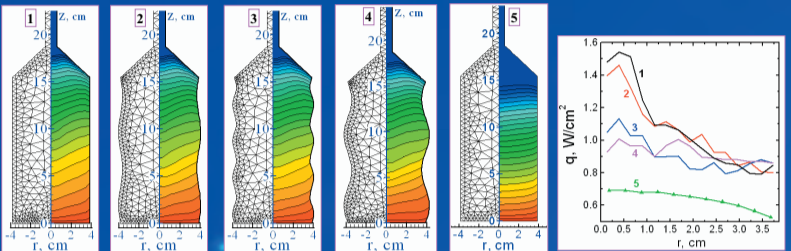


Fig.1.1. $\epsilon_1 = 0$ ($\epsilon = 0.1925 \text{ cm}$) $n_1 = 2$ Fig.1.2. $\epsilon_1 = 0.05 R_0$ ($\epsilon = 0.1925 \text{ cm}$) $n_1 = 2$ Fig.1.3. $\epsilon_1 = -0.05 R_0$ ($\epsilon = 0.1925 \text{ cm}$) $n_1 = 4$ Fig.1.4. $\epsilon_1 = 0.1 R_0$ ($\epsilon = 0.385 \text{ cm}$) $n_1 = 2$ Fig.1.5. $\epsilon_1 = 0$ and diffuse reflection on cylindrical surface. Fig.1.6. Distribution of the heat flux in solid phase over the crystallization front for the cases 1-5 shown on the left.

Resume:

Deflections of crystal lateral surface from a cylinder with straight generatrix can result to significant smoothing of the radiation heat flux distribution at the solid/liquid interface. **Therefore: wavier crystal's cylindrical surface leads to the flatter crystallization front.**

I.2 Effect of deflection of shoulder side surface from a regular conical form

From cases 1 to 3 specular reflection takes place both on the conical and cylindrical surfaces. For the case 4 reflection on the conical part of crystal surface is diffuse while on the cylindrical one is Fresnel's.

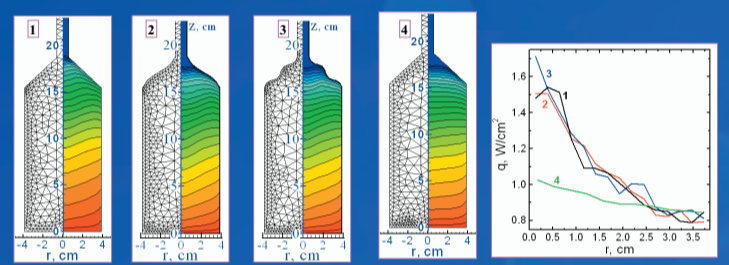


Fig.2.1. $\epsilon_2 = 0$ ($\epsilon_2 = 0.1925 \text{ cm}$) $n_2 = 1$ Fig.2.2. $\epsilon_2 = 0.05 R_0$ ($\epsilon_2 = 0.1925 \text{ cm}$) $n_2 = 1$ Fig.2.3. $\epsilon_2 = -0.05 R_0$ ($\epsilon_2 = 0.1925 \text{ cm}$) $n_2 = 2$ Fig.2.4. $\epsilon_2 = 0$ and diffuse reflection on conical surface. Fig.2.5. Distribution of heat flux in solid phase over the crystallization front for the cases 1-4 shown on the left.

Resume:

Deflections of shoulder surface from a regular conical shape do not change the radiation heat flux distribution along the solid/liquid interface.

Calculation of reflection coefficients

Reflection coefficients for Fresnel's reflection is calculated by Fresnel formulae. For diffuse reflection they are obtained from the latter by averaging over the angle of incidence [4] (Fig.B).

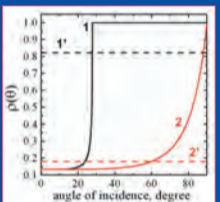


Fig.B.

- 1 – coefficient of specular reflection for radiation incident on the crystal surface from the crystal;
- 1' – coefficient of diffuse reflection for radiation incident on the crystal surface from the crystal;
- 2 – coefficient of specular reflection for radiation incident on the crystal surface from gas;
- 2' – coefficient of diffuse reflection for radiation incident on the crystal surface from gas.

Specific feature in the approach to the calculation of faceted front.

In the suggested algorithm a facet is approximated by a plane since small deflection of a facet from a close-packed surface does not influence on the heat transfer processes.

In this case a single parameter is needed (with the exception of crystallographic orientation of the facet) to define the position of the facet on the crystallization front and its size. In suggested algorithm the value of maximal supercooling is selected as this parameter.

Described approach is a numerical expansion of the analytical one suggested in [5].

I. Results of simulation for Fresnel's reflection in the absence of cylindrical part of the crystal.

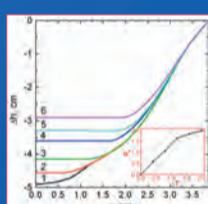


Fig.1. Shape of the interface for ΔT_{max} : 1 - 0K; 2 - 0.45K; 3 - 0.8K; 4 - 1.2K; 5 - 1.6K; 6 - 1.8K. Involved graph: dependence of radius of a facet on the supercooling ΔT_{max}

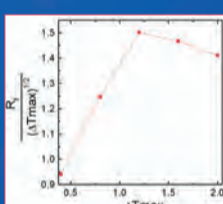


Fig.2. Dependence of relation $R_f / \sqrt{\Delta T_{max}}$ on ΔT_{max}

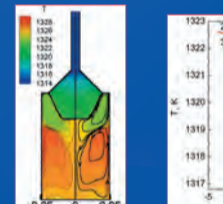


Fig.3. Temperature fields in the crystal and the melt (left) and streamlines in the melt (right) for calculated shape of the interface for $\Delta T_{max} = 1.2 \text{ K}$

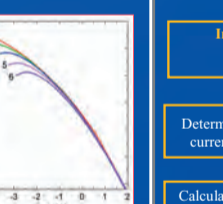
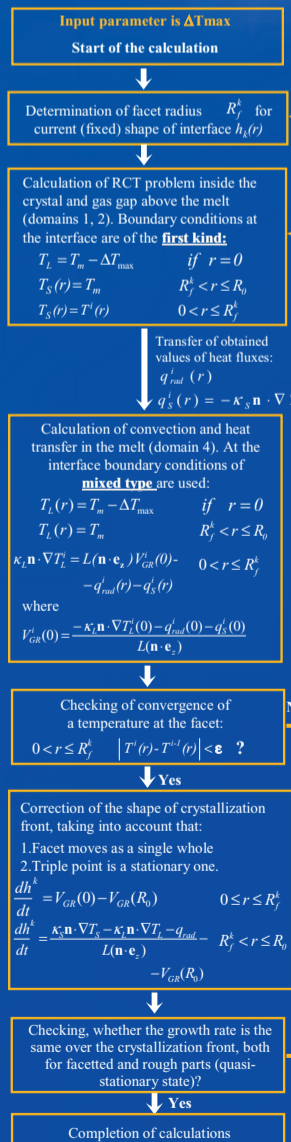


Fig.4. Temperature distribution along the axis of symmetry in the crystal for different values of ΔT_{max} : 1 - 0 K; 2 - 0.45 K; 3 - 0.8K; 4 - 1.2K; 5 - 1.6K; 6 - 1.8K

Chart of calculation procedure of the interface shape with the horizontal flat (central) facet:



Boundary conditions at the interface are of the **first kind**:

$$T_l = T_m - \Delta T_{max} \quad \text{if } r = 0$$

$$T_l(r) = T_m \quad R_f^k < r \leq R_0$$

$$T_s(r) = T^l(r) \quad 0 < r \leq R_f^k$$

where

$$T_l(r) = T_m - \Delta T_{max} \quad \text{if } r = 0$$

$$T_l(r) = T_m \quad R_f^k < r \leq R_0$$

$$\kappa_s n \cdot \nabla T_l = L(n \cdot e_s) V_{cr}^k(0) - q_{rad}^k(r) - q_s^k(r)$$

$$V_{cr}^k(0) = -\kappa_s n \cdot \nabla T_l(0) - q_{rad}^k(0) - q_s^k(0) / L(n \cdot e_s)$$

Checking of convergence of a temperature at the facet:

$$0 < r \leq R_f^k \quad |T(r) - T^{(j)}(r)| < \epsilon ?$$

Correction of the shape of crystallization front, taking into account that:

1. Facet moves as a single whole
2. Triple point is a stationary one.

Checking, whether the growth rate is the same over the crystallization front, both for faceted and rough parts (quasi-stationary state)?

Completion of calculations

1. V.S.Yuferev, O.N.Budenkova, M.G.Vasiliev, S.A.Rukolaine et al. *J. Cryst. Growth*, 253 (2003) 383.
2. Y. Liu, A. Virozub, S.Brandon, *J. Crystal Growth* 205 (1999) 333.
3. C.W. Lan, C.Y. Tu, Y.F. Lee, *Int. J. of Heat and Mass Transfer* 46 (2003) 1629.
4. Ozisik M.N. "Radiative transfer and interacting with conduction and convection", 1975, A Wiley-Interscience Publication.
5. V.S.Yuferev, E.Kh. Lokharu, J. Technical Physics, 54 (1984) 1685 (in Russian)
6. V.V.Voronkov, *Crystallography*, 17 (1972) 909 (in Russian).

II. Results of simulation for Fresnel's reflection on the shoulder's surface (AB - A'B' shown in Fig.A) and diffuse on the cylindrical one (CA - C'A' shown in Fig.A).

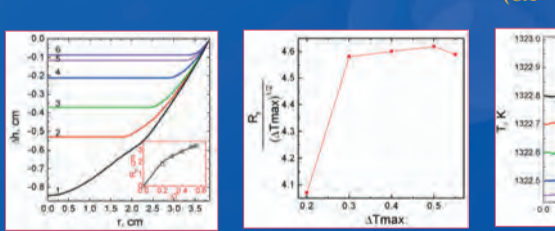


Fig.5. Shape of the interface for ΔT_{max} : 1 - 0K; 2 - 0.2K; 3 - 0.4K; 4 - 0.4K; 5 - 0.5K; 6 - 0.55K. Involved graph: dependence of radius of a facet R_f on the supercooling ΔT_{max}

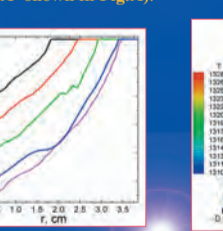


Fig.6. Dependence of relation $R_f / \sqrt{\Delta T_{max}}$ on ΔT_{max}

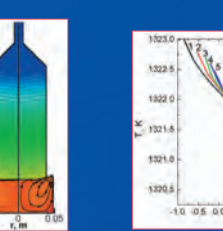


Fig.7. Temperature distribution over the interface for different supercooling ΔT_{max}

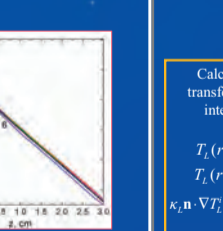


Fig.8. Temperature fields in the crystal and the melt (left) and streamlines in the melt (right) for calculated shape of the interface for $\Delta T_{max} = 0.3 \text{ K}$

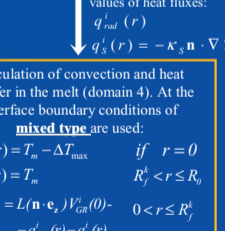


Fig.9. Temperature distribution along the axis of symmetry in the crystal for different values of supercooling ΔT_{max} : 1 - 0K; 2 - 0.2K; 3 - 0.2K; 4 - 0.4K; 5 - 0.5K; 6 - 0.55 K

III. Results of simulation for Fresnel's reflection on the whole crystal side surface.

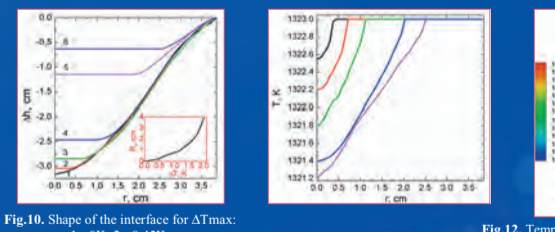


Fig.10. Shape of the interface for ΔT_{max} : 1 - 0K; 2 - 0.45K; 3 - 0.8K; 4 - 1.2K; 5 - 1.6K; 6 - 1.8K. Involved graph: dependence of radius of a facet R_f on the supercooling ΔT_{max}

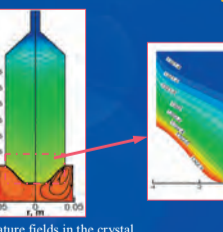


Fig.11. Temperature distribution over the interface for different supercooling ΔT_{max}

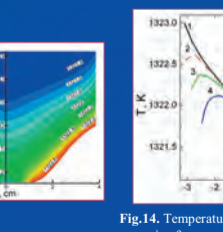


Fig.12. Temperature fields in the crystal and the melt (left) and streamlines in the melt (right) for calculated shape of the interface for $\Delta T_{max} = 1.2 \text{ K}$

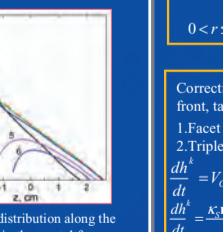


Fig.13. Temperature fields in the crystal near the crystallization front for $\Delta T_{max} = 1.2 \text{ K}$

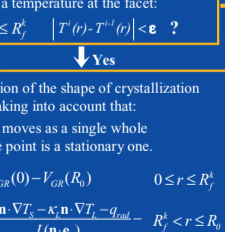


Fig.14. Temperature distribution along the axis of symmetry in the crystal for different values of supercooling ΔT_{max} : 1 - 0K; 2 - 0.45 K; 3 - 0.8 K; 4 - 1.2 K; 5 - 1.6 K; 6 - 1.8 K

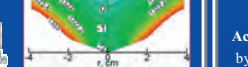
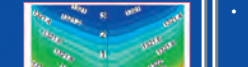
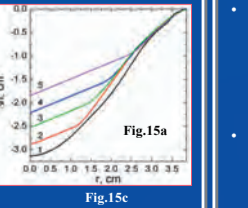
IV. Results of simulation of a set of oblique facets.

Inclined facets require 3D simulation both for liquid and solid phase. However, in the present work the system of inclined facets was replaced by a "conical facet". In Fig.15a-c results of simulation of facets [112] are presented.

Fig.15a: Shape of the interface for ΔT_{max} : 1 - 0K; 2 - 0.4K; 3 - 0.8K; 4 - 1.2K; 5 - 1.4K

Fig.15b: Temperature fields in the crystal and the melt (left) and streamlines in the melt (right) for calculated shape of the interface for $\Delta T_{max} = 1.2 \text{ K}$

Fig.15c: Temperature fields in the crystal near the crystallization front for $\Delta T_{max} = 1.2 \text{ K}$



Conclusions:

Part I.

- The influence of the deflections in the shape of a crystal on the radiative heat removal from melt/liquid interface is investigated as applied to the $\text{Bi}_4\text{Ge}_3\text{O}_{12}$ low-thermal gradients Cz method.
- It is shown that perturbations of the specular cylindrical part of crystal surface can be replaced by the diffuse reflective unperturbed surface.
- On the other hand, the shoulder surface of oxide crystals has to be treated as a specular one both in unperturbed and perturbed cases.

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Part II.

1. The algorithm of calculation of the faceted solid/liquid interface in Cz process along with RHT process is suggested.
2. It is shown that for the case of low front's convexity (when the crystal's cylindrical surface is diffuse reflecting) the effect of radiative transfer turns out insignificant. The dependence of the size of a facet for this case appears to be close to the known root law [6].
 $R_f \sim \sqrt{\Delta T_{max}}$
3. For the cases of large convexity of the melt/liquid interface (the case of specular reflection) the effect of internal radiation on the facet formation turns out very significant. In this case RT leads to the appearance of bottleneck temperature field in crystal and to a more strong dependence of the facet size on supercooling than the root law